

### FEATURES

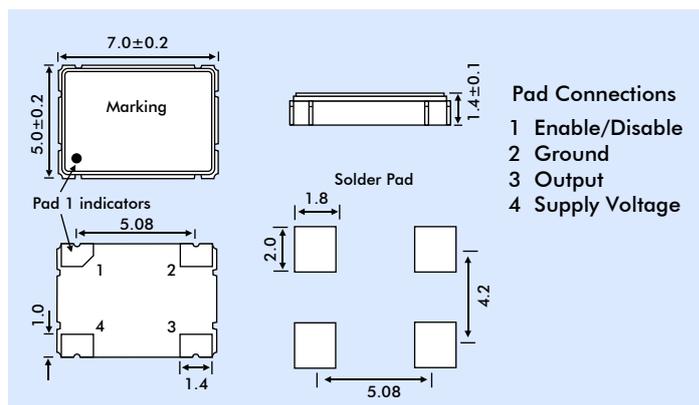
- 2.0MHz to 60.0MHz frequency range
- Wide operating temp -40° to +105°C
- Ruggedised design to 3000G shock survivability
- Designed for demanding industrial applications
- Superior phase noise performance
- Femto second integrated phase jitter 150fs (typ)
- Custom crystal pre-ageing options available
- Supply Voltages: 2.5V and 3.3V
- X-tal Stabilisation: pre-age bake beyond 96hrs @ 100C
- Made in UK - ITAR RESTRICTION FREE



### DESCRIPTION

EQXO-75UIE series is a ruggedised high-reliability, high temp clock oscillator in a standard format 7x5mm SMD ceramic package with hermetic weld-sealed metal lid. Designed by Euroquartz for demanding industrial applications, it will provide reliable operation with good frequency stability across an extended industrial operating temp band of -40C to +105C. Mechanical shock survivability tested to 3000G MIL-STD-883K Meth 2002.5, Condition C. Temp stability  $\pm 50, 75$  &  $100$ ppm are available with tighter options upon request (conditions dependant). This component is manufactured within our cleanroom facility in the south west UK, therefore comes free of ITAR restriction and can be produced with short lead time. Tighter ageing spec is available on request - all crystals are pre-aged as part of an additional process to aid long-term application stability.

### OUTLINE & DIMENSIONS



### SPECIFICATION

| Model Number  | EQXO-75UIE  |  |
|---|---|--|
| Frequency Range   | 2.0MHz to 60.000MHz   |  |
| Output Logic  | LVCMOS  |  |
| Supply Voltage V <sub>DD</sub>  | +2.5V, +3.3V ±10%   |  |
| Voltage Level: Logic Hi "1"<br>Logic Lo "0"                               | 90% of V <sub>DD</sub> (min.)<br>10% of V <sub>DD</sub> (max.)  |  |
| Current Consumption: 2.0~19.99MHz<br>20~60.00MHz<br>Output State Disabled | 6mA (max.)<br>16mA (max.)<br>10µA (max.)  |  |
| Rise Time (Tr) / Fall Time (Tf)   | 10ns (max) measured 10% ~ 90% waveform  |  |
| Load  | 15pF (max.)   |  |
| Start-up Time   | 3ms (max)   |  |
| Duty Cycle  | 50% ±5%   |  |
| Enable/Disable Function   | Enable/Disable function on Pad 1 is standard for EQXO-75UIE series oscillators<br>70% of V <sub>DD</sub> (min) Enable Output<br>30% of V <sub>DD</sub> (max) Disable Output |  |
| Phase Jitter (RMS) [26MHz, 3.3V]  | 150 fs typical (12kHz to 20MHz integrated)  |  |

| SSB Phase Noise [25MHz, 3.3V] | Offset                       | 10Hz | 100Hz | 1kHz | 10kHz | 100kHz | 1MHz | 5MHz |
|-------------------------------|------------------------------|------|-------|------|-------|--------|------|------|
|                               | dBc/Hz (typical)             | -96  | -129  | -142 | -159  | -164   | -163 | -164 |
| Storage Temperature           | -65° to +150°C               |      |       |      |       |        |      |      |
| Ageing at 25°C                | ±1ppm maximum for first year |      |       |      |       |        |      |      |
| Solder Profile                | 260°C max.                   |      |       |      |       |        |      |      |

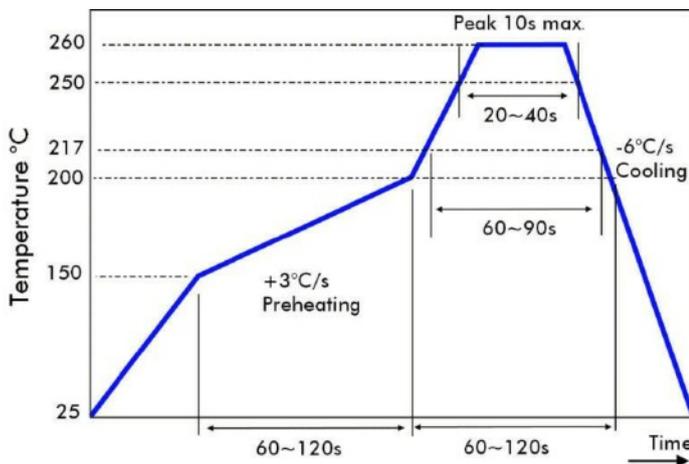
**DESIGN QUALIFICATION APPROVAL & ENVIRONMENTAL SPECIFICATION**

|                      |   |
|----------------------|---|
| Thermal Shock:       | MIL-STD-883F Method 1011.9 Condition B                              |
| Mechanical Shock:    | MIL-STD-883K Method 2002.5 Condition C                              |
| Vibration:           | MIL-STD-883F Method 2007.3  |
| High Temp Storage:   | MIL-STD-202 Method 108  |
| Moisture Resistance: | JIS C7021:B-11  |
| Seal:                | Fine leak not to exceed 1x10 <sup>-8</sup> mB litres of He leakage. |
| Solderability:       | MIL-STD-883E Method 2003.7  |

**OPTIONAL SCREENING**

Screening in accordance with MIL-O-55310C Class B  
All devices are 100% tested to the following conditions:

|                        |  |
|------------------------|--|
| Temp Cycling:          | -55C to +105C, 10 cycles.                                    |
| Constant Acceleration: | 49000m/s <sup>2</sup> for 1 min in XY plane.                 |
| Seal:                  | Fine leak not to exceed 1 x 10 <sup>-8</sup> mB litres of He |
| Dynamic Burn-in:       | 105C for 168 hrs   |
| Electrical Test:       | Frequency, output waveform, output Voltage input current.    |

**SOLDER TEMPERATURE PROFILE****ORDERING/PART NUMBER GENERATION**

Example: 20.000MHz EQXO-75UIE050EAC

Frequency ←

Series Designation ←

Stability:

050 = ±50ppm

075 = ±75ppm

100 = ±100ppm

(For tighter stability, ask)

Operating Temperature Range:

I = -40° to + 85°C

E = -40° to + 105°C

Supply Voltage:

A = 3.3 Volts

B = 2.5 Volts

Optional Crystal Pre-Ageing:

Left Blank = Standard (additional 96hr oven pre-aged)

C = Custom Crystal Pre-age (contact sales)